


<b>Search Notes</b> 	<b>Application/Control No.</b> 10533237	<b>Applicant(s)/Patent Under Reexamination</b> TANAKA ET AL.
	<b>Examiner</b> Bao-Thuy L. Nguyen	<b>Art Unit</b> 1641

SEARCHED			
Class	Subclass	Date	Examiner
436	514, 518, 523, 524, 532, 534, 823, 824	11/13/08	BTN
435	287.1; 287.2	11/13/08	BTN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, NPL	11/13/08	BTN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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